D2932, MARCH 1987 -- REVISED JANUARY 1989

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs
- Dependable Texas Instruments Quality and Reliability

### description

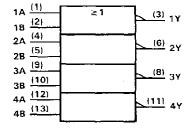
These devices contain four independent 2-input NOR gates. They perform the Boolean functions  $Y = \overline{A} + \overline{B}$  or  $Y = \overline{A} \cdot \overline{B}$  in positive logic.

The SN54F36 is characterized for operation over the full military temperature range of  $-55\,^{\circ}\text{C}$  to 125 °C. The SN74F36 is characterized for operation from 0 °C to 70 °C.

FUNCTION TABLE (each gate)

INP	JTS	OUTPUT
А	В	Υ
Н	Х	L
Х	н	Ļ
L	L	н

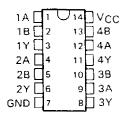
# logic symbol†



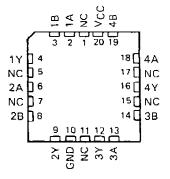
<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, and N packages.

SN54F36 . . . J PACKAGE SN74F36 . . . D OR N PACKAGE (TOP VIEW)

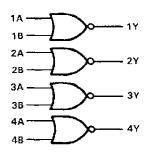


\$N54F36 . . . FK PACKAGE (TOP VIEW)



NC-No internal connection

# logic diagram (positive logic)



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCCC	).5 V to 7 V
Input voltage <sup>†</sup> –1	1.2 V to 7 V
Input current	mA to 5 mA
Voltage applied to any output in the high state	.5 V to VCC
Current into any output in the low state	40 mA
Operating free-air temperature range: SN54F36	<sup>3</sup> C to 125°C
SN74F36 0	°C to 70°C
Storage temperature range65°	°C to 150°C

<sup>&</sup>lt;sup>†</sup>The input voltage ratings may be exceeded provided the input current ratings are observed.

#### recommended operating conditions

			SN54F36			SN74F36		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
ViH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ΊΚ	input clamp current			- 18			- 18	mA
ІОН	High-level autput current			- 1			-1	mA
lOL	Low-level output current		-	20			20	mA
τ <sub>A</sub>	Operating free-air temperature	- 55		125	0		70	°C

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS			SN54F36				SN74F36		
FARAMETER		MIN	TYP‡	MAX	MIN	TYP <sup>‡</sup>	MAX	UNIT		
VIK	$V_{CC} = 4.5 \text{ V},$	l <sub>l</sub> = −18 mA		,	-1.2			-1.2	V	
VoH	$V_{CC} = 4.5 V$ ,	$l_{OH} = -1 \text{ mA}$	2.5	3.4		2.5	3.4		V	
	$V_{CC} = 4.75 V_{c}$	IOH = -1 mA				2.7			·	
V <sub>OL</sub>	$V_{CC} = 4.5 \text{ V},$	I <sub>OL</sub> = 20 mA		0.30	0.5		0.30	0.5	V	
<u> </u>	V <sub>CC</sub> = 5.5 V,	V <sub>1</sub> = 7 V			0.1			0.1	mA	
lн	V <sub>CC</sub> = 5.5 V,	V <sub>1</sub> ≈ 2.7 V			20			20	μA	
lį į	V <sub>CC</sub> = 5.5 V,	$V_1 = 0.5 \text{ V}$			-0.6	-		-0.6	mΑ	
IOS §	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0	-60		~ 150	-60		- 150	mA	
Іссн	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0		3.7	5.6		3.7	5.6	mA	
<sup>I</sup> CCL	$V_{CC} = 5.5 V_{r}$	See Note 1		8.7	13		8.7	13	mA	

# switching characteristics (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V <sub>CC</sub> = 5 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω, T <sub>A</sub> = 25°C			V <sub>CC</sub> = 4.5 V to 5.5 V, C <sub>L</sub> = 50 pF, R <sub>L</sub> = 500 Ω, T <sub>A</sub> = MIN to MAX <sup>¶</sup>				UNIT	
						SN54F36		SN74F36		}	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX		
t <sub>PLH</sub>	A or B	A == B	~	1.7	4	5.5	1.7	7.5	1.7	6.5	
tPHL		1	1	2.8	4.3	1	6.5	1	5.3	ns	

 $<sup>^{\</sup>ddagger}$ All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25 °C.

<sup>2.</sup> Load circuits and waveforms are shown in Section 1.



Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second.

<sup>1</sup> For conditions shown as MIN or MAX, use the appropriate value specified under Recommended Operating Conditions.

NOTES: 1. I $_{\mbox{CCL}}$  is measured with one input per gate at 4.5 V and all others grounded.

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